



PRODUCT AND PROCESS CHANGE NOTIFICATION

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ISSUE DATE: 26-Feb-2016
NOTIFICATION: 17122
TITLE: MC33879APEK/R2 Cold Temperature Test Elimination
EFFECTIVE DATE: 24-Aug-2016

DEVICE(S)

MPN
MC33879APEK
MC33879APEKR2

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AFFECTED CHANGE CATEGORIES

- TEST PROCESS

DESCRIPTION OF CHANGE

NXP Semiconductors announces the cold temperature test elimination from the Final Test production flow for the MC33879APEK/R2 devices associated with this notification. Cold test performance is covered by the remaining Final Test production flow. The cold test elimination has been successfully qualified according to NXP specifications.

Current Production Final Test Flow:
Hot - Cold

New Production Final Test Flow:
Hot

REASON FOR CHANGE

Improve capacity for optimized cycle time and delivery.

ANTICIPATED IMPACT OF PRODUCT CHANGE(FORM, FIT, FUNCTION, OR RELIABILITY)

No change to form, fit, function or reliability.

According to JEDEC Standard JESD46, lack of acknowledgement of this PCN within 30 days will be considered acceptance of change. To request further data or inquire about the notification, please enter a [Support Case](#). **Be aware that after you select this link to enter your request, you must choose the topic "Product Change Notification" once on the Salesforce page.**

For sample inquiries - please go to www.nxp.com

QUAL DATA AVAILABILITY DATE: 28-Aug-2015

QUALIFICATION STATUS: COMPLETED

QUALIFICATION PLAN:

NXP Semiconductors standard specification for Test Elimination was followed for this change. See attached Qualification Report.

RELIABILITY DATA SUMMARY:

Product is fully qualified. No further reliability data is needed for this change.

ELECTRICAL CHARACTERISTIC SUMMARY:

No change to Electrical Distributions.

CHANGED PART IDENTIFICATION:

There is no change to orderable part number or marking.

ATTACHMENT(S):

External attachment(s) FOR this notification can be viewed AT:

[17122_MC33879APEK_Cold_Temp_Elimination_Qualification_Results.pdf](#)

[17122_MC33879APEK_Cold_Temp_Elimination_Delta-Qualification-Matrix-ZVEI.pdf](#)
